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Nov. 2016

FPF2C110BI07AS2

F2, Boost and Inverter module with Press-fit

General Description

Fairchild's Boost and H-Bridge module is designed for a power stage that needs more compact design. And the Press-fit technology provides simple and reliable mounting. This module is optimized for the application such as solar inverter where a high efficiency and robust design are needed.

Electrical Features

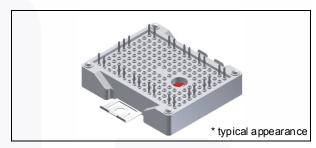
- · Boost Stage
 - Dual Boost Topology
 - SiC Boost Diode
 - Low R_{DS(ON)} Boost Switch
 - Low V_F and High Voltage Bypass Diode
- · Inverter Stage
 - H-bridge Topology
 - High Speed IGBT and Fast Recovery FWD
- · Integrated DC-capacitor for Boost and Inverter
- · Temperature Sensor

Mechanical Features

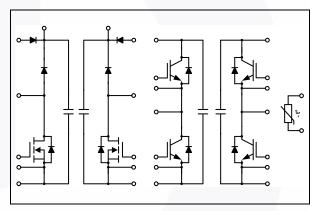
- · Compact size: F2 Package
- Press-fit Contact Technology
- Al₂O₃ Substrate with Low Thermal Resistance

Applications

Solar Inverter



Package Code: F2



Internal Circuit Diagram

Package Marking and Ordering Information

Device	Device Marking	Package	Packing Type	Quantity / Tray
FPF2C110BI07AS2	FPF2C110BI07AS2	F2	Tray	14

Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Description	Condition	Rating	Units	
Bypass Dio	ode (DA1, DA2)				
V _{RRM}	Peak Repetitive Reverse Voltage		1000	V	
l _F	Continuous Forward Current	T _C = 80 °C, T _{Jmax} = 175 °C	50	Α	
I _{FSM}	Non-repetitive Peak Surge Current	60 Hz Single Half-Sine Wave	350	Α	
l ² t	Surge Current Integral Value		510	A ² s	
P_{D}	Maximum Power Dissipation	T _{Jmax} = 175 °C	300	W	
T _J	Operating Junction Temperature		- 40 to + 150	°C	
Boost Diod	le (DB1, DB2)				
V _{RRM}	Peak Repetitive Reverse Voltage		650	V	
l _F	Continuous Forward Current	T _C = 80 °C, T _{Jmax} = 175 °C	10	Α	
I _{FSM}	Non-repetitive Peak Surge Current	60 Hz Single Half-Sine Wave	40	Α	
I ² t	Surge Current Integral Value		6.6	A ² s	
P _D	Maximum Power Dissipation	T _{Jmax} = 175 °C	90	W	
T _J	Operating Junction Temperature		- 40 to + 150	°C	
Boost MOS	FET (M1, M2)				
V _{DSS}	Drain-Source Voltage		650	V	
V _{GSS}	Gate-Source Voltage		± 20	V	
I _D	Drain Current	T _C = 25 °C, T _{Jmax} = 150 °C	25	Α	
		T _C = 80 °C, T _{Jmax} = 150 °C	19	Α	
I _{DM}	Pulsed Drain Current	limited by T _{Jmax}	50	Α	
P _D	Maximum Power Dissipation	T _{Jmax} = 150 °C	199	W	
 T _J	Operating Junction Temperature		- 40 to + 150	°C	
H-bridae IG	BBT (QA, QB, QC, QD)				
V _{CES}	Collector-Emitter Voltage		650	V	
V _{GES}	Gate-Emitter Voltage		± 20	V	
I _C	Collector Current	T _C = 80 °C, T _{Jmax} = 175 °C	40	Α	
I _{CM}	Pulsed Collector Current	limited by T _{Jmax}	80	А	
P_{D}	Maximum Power Dissipation	T _{Jmax} = 175 °C	158	W	
T _J	Operating Junction Temperature		- 40 to + 150	°C	
H-bridge F\	WD (QAD, QBD, QCD, QDD)				
V _{RRM}	Peak Repetitive Reverse Voltage		650	V	
I _F	Diode Forward Current	T _C = 80 °C, T _{Jmax} = 175 °C	30	Α	
I _{FM}	Pulsed Maximum Forward Currents	limited by T _{Jmax}	60	Α	
P _D	Maximum Power Dissipation	T _{Jmax} = 175 °C	109	W	
T _J	Operating Junction Temperature		- 40 to + 150	°C	
DC Link Ca	pacitor			1	
V _{MAX}	Maximum DC Voltage		1000	V	
T _{OP}	Operating Temperature		- 55 to + 125	°C	

Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Description	Condition	Rating	Units
Module	•	,		•
T _{STG}	Storage Temperature		- 40 to + 125	°C
V _{ISO}	Isolation Voltage	AC 1 min.	2500	
IsoMaterial	Internal Isolation Material	Al ₂ O ₃	-	
T _{MOUNT}	Mounting Torque ₍₁₎		2.4	N•m
Creepage	Terminal to Heat Sink		11.5	mm
	Terminal to Terminal		6.3	mm
Clearance	Terminal to Heat Sink		10.0	mm
	Terminal to Terminal		5.0	mm

Notes:

1. Recommendable value: 2.0 ~ 2.4 Nm (M4)

$\textbf{Electrical Characteristics} \ \, \textit{T}_{\textit{C}} = 25 \, ^{\circ}\textit{C} \ \, \text{unless otherwise noted.} \, \textbf{Parantheses value is based on the discrete.}$

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
Bypass D	liode (DA1, DA2)					
V _F	Diode Forward Voltage	I _F = 50 A	-	1.37	1.7	V
		I _F = 50 A, T _C = 125 °C	-	1.3	-	V
I _R	Reverse Leakage Current	V _R = 1000 V	-	-	250	μА
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Diode	-	-	0.49	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink	per Chip, λ_{PCM} = 3.4 W/mK	-	0.56	-	°C/W
Boost Dic	ode (DB1, DB2)					
V _F	Diode Forward Voltage	I _F = 10 A	-	1.42	1.58	V
		I _F = 10 A, T _C = 125 °C	-	1.61	-	V
I _R	Reverse Leakage Current	V _R = 650 V	-	-	250	μА
I _{rr}	Reverse Recovery Current	V _R = 300 V, I _F = 10 A,	-	6	-	Α
Q _C	Total Capacitive Charge	di / dt = 1560 A/us,	-	60	-	nC
E _{rec}	Reverse Recovery Energy	T _C = 25 °C	-	7.5	-	μJ
I _{rr}	Reverse Recovery Current	V _R = 300 V, I _F = 10 A,	-	6	\ -	A
Q _C	Total Capacitive Charge	di / dt = 1560 A/us,	-	61	-	nC
E _{rec}	Reverse Recovery Energy	T _C = 125 °C	-	7.5	-	μJ
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Chip	-	-	1.63	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink	per Chip, λ _{PCM} = 3.4 W/mK	-	0.42	-	°C/W
Boost MC	OSFET (M1, M2)			•		
Off Charac						
V_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V, } I_D = 1 \text{ mA}$	650	-	-	V
I _{DSS}	Drain Cut-off Current	$V_{DS} = V_{DSS}, V_{GS} = 0 V$	-	-	250	μА
I _{GSS}	Gate-Source Leakage Current	V _{GS} = V _{GSS} , V _{DS} = 0 V	-	-	± 1	μА
On Charac	teristics					
V _{GS(th)}	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250uA$	3.0	3.9	5.0	V
R _{DS(ON)}	Static Drain-Source On Resistance	I _D = 17.5 A, V _{GS} = 10 V	-	110	137	mΩ
V _{SD}	Drain-Source Diode Forward Voltage	I _{SD} = 17.5 A, V _{GS} = 0 V	-	1.07	1.37	V
		I _{SD} = 17.5 A, V _{GS} = 0 V, T _C = 125 °C	-	0.93	-	V
R _{LEAD}	Lead Resistance of Pin to Chip	per Chip	-	3.2	-	mΩ
Switching	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{CC} = 300 V	-	27	-	ns
t _r	Rise Time	I _D = 17.5 A	-	5.0	-	ns
$t_{d(off)}$	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}$ $R_G = 4.7 \Omega$	-	3.0	-	ns
t _f	Fall Time	Inductive Load	-	5.5	-	ns
E _{ON}	Turn-On Switching Loss per Pulse	T _C = 25 °C	-	33	/ -	μJ
E _{OFF}	Turn-Off Switching Loss per Pulse		-	20	-	μJ
t _{d(on)}	Turn-On Delay Time	V _{CC} = 300 V	-	26	-	ns
t _r	Rise Time	I _D = 17.5 A	-	5.3	-	ns
t _{d(off)}	Turn-Off Delay Time	V_{GS} = 10 V R_{G} = 4.7 Ω Inductive Load T_{C} = 125 °C	-	87	-	ns
t _f	Fall Time		-	6.0	-	ns
E _{ON}	Turn-On Switching Loss per Pulse		-	39	-	μJ
E _{OFF}	Turn-Off Switching Loss per Pulse		-	21	-	<u>.</u> μJ
$\overline{Q_g}$	Total Gate Charge	V _{CC} = 300 V, I _{SD} = 17.5 A, V _{GS} = 10 V	-	84	-	nC
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Chip	-	-	0.63	°C/W
R _{θCH}	Thermal Resistance of Case to Heat sink	per Chip, λ _{PCM} = 3.4 W/mK	_	0.49	-	°C/W

$\textbf{Electrical Characteristics} \ \ \textbf{T}_{\text{C}} = 25\ ^{\circ}\text{C unless otherwise noted.} \ \textbf{Parantheses value is based on the discrete.}$

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
H-Bridge	IGBT (QA, QB, QC, QD)					
Off Charac	teristics					
BV _{CES}	Collector-Emitter Breakdown Voltage	$V_{GE} = 0 \text{ V}, I_{C} = 1 \text{ mA}$	650	-	-	V
I _{CES}	Collector Cut-off Current	$V_{CE} = V_{CES}, V_{GE} = 0 V$	-	-	250	μΑ
I _{GES}	Gate-Emitter Leakage Current	$V_{GE} = V_{GES}$, $V_{CE} = 0$ V	-	-	± 2	μΑ
On Charac	teristics					
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}$, $I_C = 40 \text{ mA}$	3.0	5.2	6.1	V
V _{CE(sat)}	Collector-Emitter Saturation Voltage	I _C = 40 A, V _{GE} = 15 V	-	1.6	2.3	٧
		I_C = 40 A, V_{GE} = 15 V, T_C = 125 °C	-	1.8	-	V
R _{LEAD}	Lead Resistance of Pin to Chip	per Chip	-	3.5	-	mΩ
Switching	Characteristics (QB-QAD / QD-QCD)					
t _{d(on)}	Turn-On Delay Time	V _{CC} = 300 V	-	26	-	ns
t _r	Rise Time	I _C = 40 A - V _{GE} = 15 V	-	22	-	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 15 \Omega$	-	125	-	ns
t _f	Fall Time	Inductive Load	-	14	-	ns
E _{ON}	Turn-On Switching Loss per Pulse	T _C = 25 °C	-	0.45	-	mJ
E _{OFF}	Turn-Off Switching Loss per Pulse			0.27	-	mJ
t _{d(on)}	Turn-On Delay Time	V _{CC} = 300 V	-	24	-	ns
t _r	Rise Time	I _C = 40 A	-	25	-	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GE} = 15 \text{ V}$ $R_{G} = 15 \Omega$	-	139	-	ns
t _f	Fall Time	Inductive Load	-	13	-	ns
E _{ON}	Turn-On Switching Loss per Pulse	T _C = 125 °C	-	0.74	-	mJ
E _{OFF}	Turn-Off Switching Loss per Pulse		-	0.35	-	mJ
Qg	Total Gate Charge	V _{CC} = 300 V, I _C = 40 A, V _{GE} = 15 V	-	60	-	nC
$R_{\theta JC}$	Thermal Resistance of Junction to Case	per Chip	-	-	0.95	°C/W
$R_{\theta CH}$	Thermal Resistance of Case to Heat sink per Chip, λ_{PCM} = 3.4 W/mK		-	0.64	-	°C/W
H-bridge	FWD (QAD, QBD, QCD, QDD)					
V _F	Diode Forward Voltage	I _E = 30 A	-	2.45	3.2	V
*F	Blodd Forward Vollage	I _F = 30 A, T _C = 125 °C	-	2.15	-	V
I _R	Reverse Leakage Current	V _R = 650 V		-	250	μА
I _{rr}	Reverse Recovery Current	V _R = 300 V, I _F = 30 A,	/-	20.1		A
t _{rr}	Reverse Recovery Time	di / dt = 1570 A/us,	_	30	_	ns
E _{rec}	Reverse Recovery Energy	T _C = 25 °C	-	27	-	μЈ
	Reverse Recovery Current	V _R = 300 V, I _F = 30 A,	-	23.1	_	A
t _{rr}	Reverse Recovery Time	di / dt = 1135 A/us,	_	52	_	ns
E _{rec}	Reverse Recovery Energy	T _C = 125 °C	_	73	_	μЈ
R _{θJC}	Thermal Resistance of Junction to Case	per Chip	-	-	1.38	°C/W
R _{θCH}	Thermal Resistance of Case to Heat sink	per Chip, $\lambda_{PCM} = 3.4 \text{ W/mK}$	-	0.45	-	°C/W
		r r r r r r r r r r r r r r r r r r r				
DC link C				T .=		
C value	Capacitance Value		-	47	-	nF
NTC (The	rmistor)					
R _{NTC}	Rated Resistance	T _C = 25 °C	-	22	-	kΩ
		T _C = 100 °C	-	1.486	-	kΩ
	Tolerance	T _C = 25 °C	-5	-	+5	%
P_D	Power Dissipation	T _C = 25 °C	-	-	20	mW
B _{Value}	B-Constance	B _{25/50} , tol.	_	3950	-	K
		B _{25/100}	-	3998	-	K

Fig 1. Forward Voltage Drop

- Bypass Diode

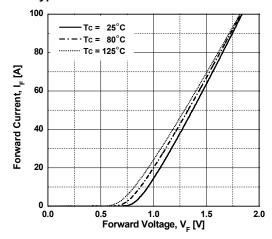


Fig 2. Transient Thermal Impedance
- Bypass Diode

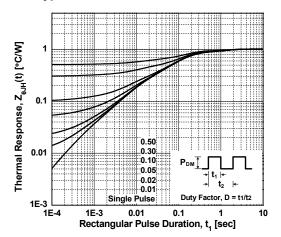


Fig 3. Forward Voltage Drop

- Boost Diode

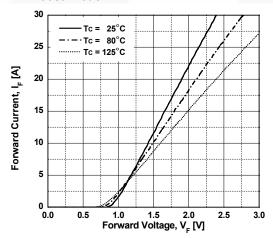


Fig 4. Transient Thermal Impedance

- Boost Diode

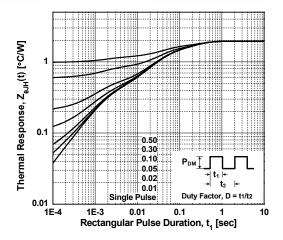


Fig 5. On-Region Characteristics

- Boost MOSFET

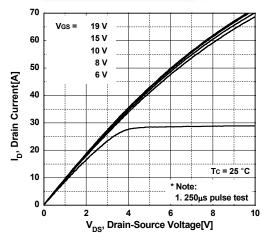


Fig 6. On-Region Characteristics

- Boost MOSFET

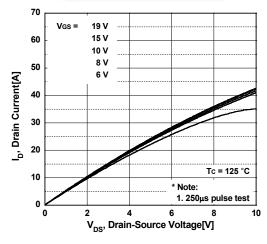


Fig 7. On-Resistance Variation vs. Temperature

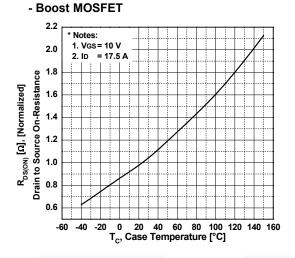


Fig 8. Switching Loss vs. Gate Resistor Values

- Boost MOSFET

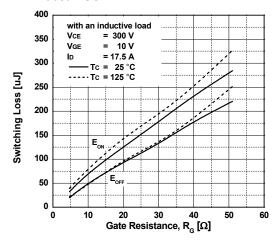


Fig 9. Switching Loss vs. Drain Current
- Boost MOSFET

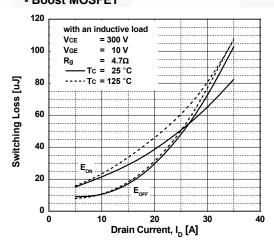


Fig 10. Body Diode Forward Voltage Variation vs.
Source Current and Temperature - Boost MOSFET

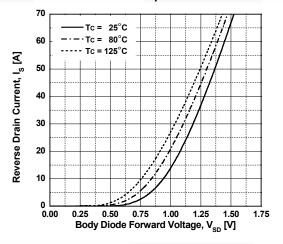


Fig 11. Transient Thermal Impedance
- Boost MOSFET

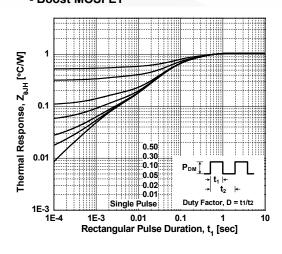


Fig 12. Output Characteristics

- H-bridge IGBT

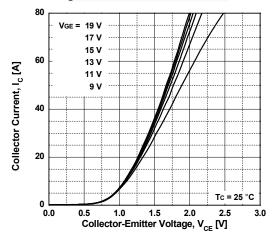


Fig 13. Output Characteristics

- H-bridge IGBT

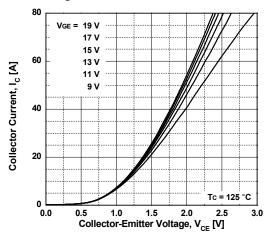


Fig 14. Saturation Voltage Characteristics
- H-bridge IGBT

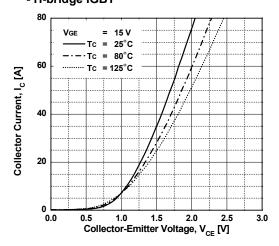


Fig 15. Switching Loss vs. Gate Resistor Values
- H-bridge IGBT

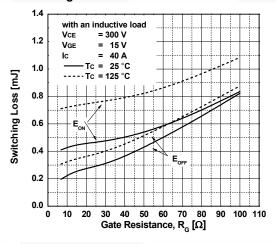


Fig 16. Switching Loss vs. Collector Current
- H-bridge IGBT

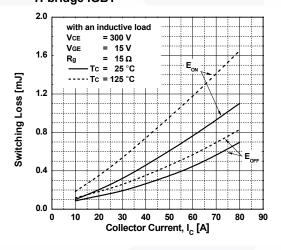


Fig 17. Transient Thermal Impedance
- H-bridge IGBT

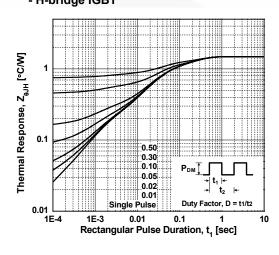


Fig 18. Forward Voltage Drop vs. Forward Current
- H-bridge FWD

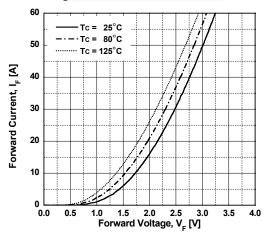


Fig 19. Reverse Recovery Energy vs.

Gate Resistor Values - H-bridge FWD

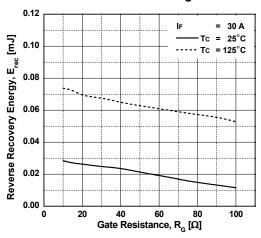


Fig 20. Reverse Recovery Energy vs.

Forward Current - H-bridge FWD

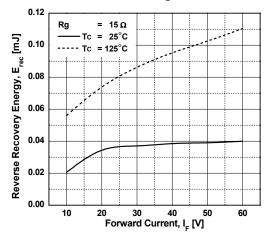
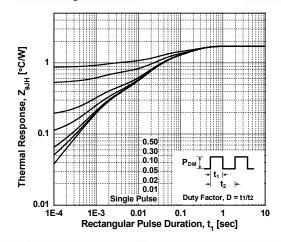
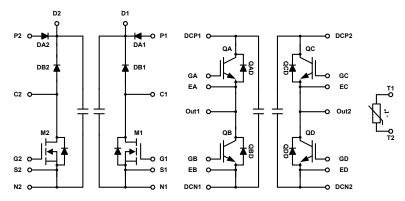


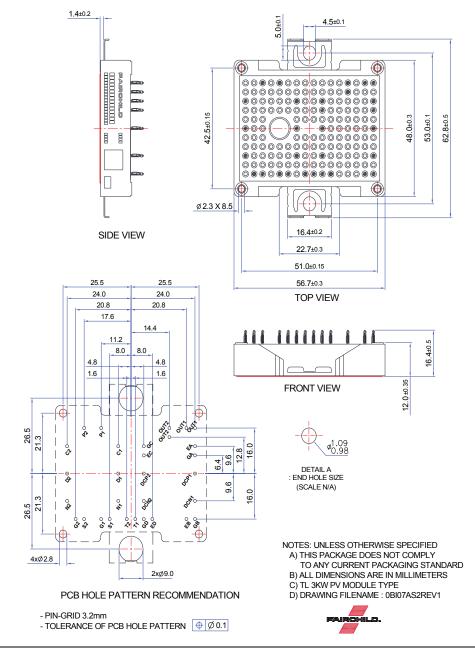
Fig 21. Transient Thermal Impedance
- H-bridge FWD



Internal Circuit Diagram



Package Outlines [mm]







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SuperSOT™-6
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TinYOPTO™
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TinyWire™
TranSiC™
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VCX™
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